

Intel® Xeon® Processor D-1500 NS Product Family and Intel® Xeon® Processor D-1600 NS Product Family

Datasheet - Volume 3 of 4: Electrical

April 2019

Document Number 336288-005US

Intel technologies' features and benefits depend on system configuration and may require enabled hardware, software or service activation. Learn more at Intel.com, or from the OEM or retailer.

No computer system can be absolutely secure. Intel does not assume any liability for lost or stolen data or systems or any damages resulting from such losses.

You may not use or facilitate the use of this document in connection with any infringement or other legal analysis concerning Intel products described herein. You agree to grant Intel a non-exclusive, royalty-free license to any patent claim thereafter drafted which includes subject matter disclosed herein.

No license (express or implied, by estoppel or otherwise) to any intellectual property rights is granted by this document. The products described may contain design defects or errors known as errata which may cause the product to deviate from published specifications. Current characterized errata are available on request.

All information provided here is subject to change without notice. Contact your Intel representative to obtain the latest Intel product specifications and roadmaps.

Intel disclaims all express and implied warranties, including without limitation, the implied warranties of merchantability, fitness for a particular purpose, and non-infringement, as well as any warranty arising from course of performance, course of dealing, or usage in trade.

Intel does not control or audit third-party benchmark data or the web sites referenced in this document. You should visit the referenced web site and confirm whether referenced data are accurate.

Copies of documents which have an order number and are referenced in this document may be obtained by calling 1-800-548- 4725 or by visiting [www.intel.com/design/literature.htm.](http://www.intel.com/design/literature.htm)

Intel and the Intel logo are trademarks of Intel Corporation in the U.S. and/or other countries.

*Other names and brands may be claimed as the property of others.

Copyright © 2019, Intel Corporation. All Rights Reserved.

Contents

Figures

Tables

Revision History

§

1 Introduction

The datasheet addendum provides functional descriptions of the Intel® Xeon® Processor D-1500 NS product family and Intel® Xeon® Processor D-1600 NS product family as they differ from the Intel® Xeon® processor D-1500 product family. This document is distributed as a part of the complete document consisting of six volumes.

Note: The Intel® Xeon® processor D-1500 NS product family and Intel® Xeon® Processor D-1600 NS product family are also referred to as the "SoC" throughout this document.

1.1 Changes to Thermal Design Power (TDP) Workload

The Intel® Xeon® D-1600 NS Processor Family has been optimized for use in some networking and storage applications. The workload assumed for maintaining the marked frequency (also called P1) at TDP is an average across the SPECint_rate2006 benchmark suite.

Note: The SPECint* benchmark is composed of 12 different sub-benchmarks.

For SKUs that offer Intel® QuickAssist Technology (Intel® QAT), it is assumed the Intel QAT engines are running a maximal Pubic Key Exchange (PKE) workload in addition to the processor core workload. The Intel® Xeon® D-1500 NS Processor Family and Intel® Xeon® D-1500 Processor Family assumed a more compute intensive core workload for the TDP operating point. Therefore, this new family of application optimized SKUs may not maintain their marked frequency while running some standard server test loads (SPECint, SPECfp*, or POV-Ray for example). Throttling can occur even if there is thermal margin to $T_{CASE-MAX}$ as TDP is enforced by the SoC.

Intel recommends potential customers perform performance testing before committing to a design using these new processors and not rely solely on experience and frequency scaling projections to estimate expected performance.

1.2 Major Differences from the Intel® Xeon® Processor D-1500 Product Family

The high level differences between the Intel® Xeon® processor D-1500 product family and the Intel® Xeon® processor D-1500 NS and D-1600 product families are given below.

- SKUs with up to 8 cores are supported.
- Removed existing 10GBASE-KX4 ports.
- Added two 10GBASE-KR ports.
- Added two Ethernet MACs supporting the additional 10GBASE-KR ports.
- Replaced Intel® QuickData Technology version 3.3 with version 3.2
- Added Intel® QuickAssist Technology hardware version 1.7

ı

1.2.1 Intel® QuickData Technology Version 3.2

The Intel QuickData Technology DMA engine supports 8 DMA channels. Its PCI configuration registers occupy functions 0-7 of device 4 on CPUBUSNO(0). PCI Device IDs are 6F20-6F27.

Only data movement commands are supported. RAID, XOR, and CRC opcodes are not supported.

Data movement commands only support memory-to-memory and memory-to-MMIO operations. MMIO-to-MMIO and MMIO-to-memory operations are not supported.

1.2.2 Intel® QuickAssist Technology

The integrated Intel® QuickAssist Technology (Intel® QAT) provides acceleration functions that can be used by the Intel® architecture cores. The acceleration services can be accessed by a standard PCIe* driver. To enhance communication between the Intel architecture and the Intel QAT, the Intel QAT implements rings via the ring controller to route messages between them.

Applications running on the Intel architecture core(s) can make use of the acceleration by calling the Intel QuickAssist Technology Application Programming Interfaces (APIs). The APIs communicate with the Intel QuickAssist Technology hardware via the PCI configuration space access and assisted rings stored in system memory.

Refer to the *Intel® QuickAssist Technology API Programmer's Guide*, which is incorporated herein by reference, and available at:

[• https://01.org/packet-processing/intel%C2%AE-quickassist-technology-drivers](https://01.org/packet-processing/intel%C2%AE-quickassist-technology-drivers-and-patches)and-patches

Features

This product contains Intel® QuickAssist Technology hardware version 1.7.

- Symmetric cryptographic functions
	- Cipher operation
	- Hash/authenticate operation
	- Cipher-hash combined operation
	- Key derivation operation
- Public key functions
	- RSA operation
	- Diffie-Hellman operation
	- Digital signature standard operation
	- Key derivation operation
	- Elliptic curve cryptography: ECDSA and ECDH
- Compression/Decompression
	- Deflate

1.2.3 Integrated 10GbE Controllers

There are four 10 GbE Media Access Control (MACs) supporting a 10GBASE_KR Physical Layer. The physical layer supports speeds of 10 GbE and 1 GbE. Each physical interface provides the following electrical modes:

- 10GBASE-KR for backplane applications (IEEE* 802.3 clause 72)
- 1000BASE-KX for backplane applications (IEEE 802.3 clause 70)
- 10GBASE-KR interface to SFI PHY (Inphi CS4227)
- 10GBASE-KR interface to 10GBASE-T PHY (Intel X557-AT or X557-AT2)

The four MACs are grouped into two pairs of MACs. Signals unique to pair are prefixed with LAN0 and LAN1. Signals which are shared among all four ports (NC-SI and SMBUS management interface) begin with LAN_.

Both ports associated with LAN0 must be configured identically (that is, both for 10GBASE-KR, both for SFI, or both for 10GBASE-T). Similarly, both ports of LAN1 must have an identical configuration. However, LAN0 and LAN1 may be configured independently.

1.3 Electrical Specification Introduction

This addendum of the *Intel® Xeon® Processor D-1500 product family* Datasheet provides DC electrical specifications and signal definitions of the processor.

The target audience for this document is primarily system architects and board designers who are planning to develop a SoC-based microserver solution. Additionally, this document is also used by other system engineers such as system test engineers, software developers, and BIOS developers.

Note: The data contained within this document is preliminary and is subject to change.This data is the most accurate information available by the publication date. Electrical DC specifications are based on estimated I/O buffer behavior.

1.4 Statement of Volatility (S0V)

The Intel® Xeon® Processor D-1500 NS product family and Intel® Xeon® Processor D-1600 NS product family does not retain any end-user data when powered down.

2 Signal Names and Descriptions

2.1 Overview

This chapter provides a detailed description of the signals and bootstrap definitions for the SoC. The signals are arranged in functional groups according to their associated interface.

Each signal description table has the following headings:

- **Signal:** The name of the signal.
- **Description:** A brief explanation of the signal function.
- **Power Rail:** Power rails used to supply power to the I/O signal are defined in [Table 2-1.](#page-10-2)

Table 2-1. Buffer Power Rails

- **Direction and Type:** The buffer direction and type.
	- Buffer direction is input (I), output (O), or bi-directional (I/O or IO).
	- Buffer Types are defined in [Table 2-2.](#page-10-3)

Table 2-2. Buffer Types

2.2 Name Convention

[Table 2-3](#page-11-2) provides the legend for interpreting the I/O Type field that appears the tables in this section.

Table 2-3. Signal Type Definitions

2.3 System DDR Memory Signals

Table 2-4. DDR Memory Signals (Sheet 1 of 4)

 $\overline{}$

Table 2-4. DDR Memory Signals (Sheet 2 of 4)

with multiple Ranks. CS# is considered part of

the command code.

 \mathbf{I}

DDR{0/1}_ECC[7:0] I/O SSTL VDDQ Check bits. An error correction code is driven
along with data on these lines for DIMMs that

Table 2-4. DDR Memory Signals (Sheet 3 of 4)

Τ

Τ

support that capability.

Table 2-4. DDR Memory Signals (Sheet 4 of 4)

2.4 PCI Express* 3.0 Interface Signals

Table 2-5. PCI Express Signals (Sheet 1 of 2)

2.5 PECI Signal

Table 2-6. PECI Signals

2.6 JTAG and TAP Signals

Table 2-7. JTAG Signals (Sheet 1 of 2)

Table 2-7. JTAG Signals (Sheet 2 of 2)

2.7 UART Signals

Table 2-8. UART Signals

2.8 Serial Interrupt Signals

Table 2-9. Serial Interrupt Request Interface Signals

2.9 SVID Signals

Table 2-10. SVID Signals

2.10 Miscellaneous Signals

Table 2-11. Misc. Signals (Sheet 1 of 5)

Table 2-11. Misc. Signals (Sheet 2 of 5)

Table 2-11. Misc. Signals (Sheet 3 of 5)

Table 2-11. Misc. Signals (Sheet 4 of 5)

Table 2-11. Misc. Signals (Sheet 5 of 5)

2.11 USB Interface

- **Note:** The USB2.0 signals in the integrated PCH integrate pull-down resistors and provide an output driver impedance of 45 Ω that requires no external series resistor. No external pull-up/pull-down resistors should be added to the USB2.0 signals. USB ports not needed can be left floating as No Connect.
- **Note:** The voltage divider formed by the device pull-up and the host pull-down will guarantee the data wire will park at a safe voltage level, which is below the VBUS value. This ensures that the host/hub will not see 5V at the wire when inter-operating with devices that have VBUS at 5V.
- **Note:** All USB 2.0 register addresses throughout the EDS correspond to the external pin names. Refer to the table below to know exactly how the USB pins are mapped to the different internal ports within the xHCI and EHCI controllers.

Table 2-12. USB Interface Signals (Sheet 1 of 2)

Table 2-12. USB Interface Signals (Sheet 2 of 2)

2.12 SATA Signals

Table 2-13. SATA2 Signals (Sheet 1 of 2)

Table 2-13. SATA2 Signals (Sheet 2 of 2)

2.13 Clock Signals

Table 2-14. Clock Signals

2.14 PCI Express Gen2 Interface Signals

Table 2-15. PCIe Express Gen 2 Interface Signals

2.15 LPC Interface Signals

Table 2-16. LPC Signals

2.16 Power Management Signals

Table 2-17. Power Management Signals (Sheet 1 of 3)

Table 2-17. Power Management Signals (Sheet 3 of 3)

2.17 Interrupt Signals

Table 2-18. Interrupt Signals

2.18 GPIO Signals

The following table summarizes the GPIOs in the PCH. The control for the GPIO signals is handled through an independent 128-byte I/O space. The base offset for this space is selected by the GPIO_BAR register in D31:F0 configuration space.

Highlights of GPIO features:

- a. Only GPIO[31:1] are blink-capable.
- b. When the default of a multiplexed GPIO is Native but the desired functionality is GPIO, care should be taken to ensure the signal is stable until it is initialized to GPIO functionality.
- c. Glitch-less Output means the signal is ensured to be stable (no glitch) during power on and when switching mode of operation from Native to GPIO or GPIO to Native. Glitch-less Input means the signal has built-in de-glitch protection that gates the input signal until power has become stable (the input is ignored during this time).
- d. The following GPIOs are capable of generating SMI_N, SCI, or NMI: GPIO[60, 57, 43, 27, 22, 21, 19, 17, 15, 14, 12:0].
- e. GPIO_USE_SEL[31:0], GPIO_USE_SEL2[63:32] and GPIO_USE_SEL3[75:64] select whether the pin is selected to function as GPIO (GPIO USE SEL[x] = 1) or Native (GPIO_USE_SEL[x] = 0). However, the PCH Soft Straps (SPI Flash) take precedence if there is a mismatch with GPIO_USE_SEL.
- f. GP_IO_SEL[31:0], GP_IO_SEL[63:32] and GP_IO_SEL[75:64] select whether the pin is an output (GP_IO_SEL[x] = 0) or an input (GP_IO_SEL[x] = 1). The value written to or reported in this register is invalid when the pin is programmed to Native function.
- g. If the corresponding GPIO has been set as an input, and GPI_ROUT has been programmed for NMI functionality, the GPI_NMI_EN[15:0] is used to allow active-high or active-low NMI events (depending on the polarity selected by GPI_INV[31:0]).
- h. All the GP_RST_SEL registers are only resettable by RSMRST_N. GPIO Configuration registers within the Core Well are reset whenever PWROK is deasserted.
- i. GPIO Configuration registers within the Suspend Well are reset when RSMRST_N is asserted, CF9h reset (06h or 0Eh), or SYS_RESET_N is asserted. However, CF9h reset and SYS_RESET_N events can be masked from resetting the Suspend well GPIO by programming appropriate GPIO Reset Select (GPIO_RST_SEL) registers.
- j. GPIO24 is an exception to the other GPIO Signals in the Suspend Well and is not reset by CF9h reset (06h or 0Eh).

Table 2-19. General Purpose I/O Signals (Sheet 1 of 4)

Table 2-19. General Purpose I/O Signals (Sheet 2 of 4)

Table 2-19. General Purpose I/O Signals (Sheet 3 of 4)

Table 2-19. General Purpose I/O Signals (Sheet 4 of 4)

Notes:

1. GPIO24 register bits are not cleared by CF9h reset by default, it is programmable through GP_RST_SEL[24].

- 2. Internal pull up or pull down may be present when Native functionality is selected.
3. Internal pull down resistor may be enabled in Deen Sy mode based on DSX, CEG c
- 3. Internal pull down resistor may be enabled in Deep Sx mode based on DSX_CFG configuration bit, as follows: '1' (pin will be driven by platform in Deep Sx) -> Z; - '0' (pin will NOT be driven by platform in Deep Sx) -> Internal pull-down. Refer to the DSX_CFG register (RCBA+3334h) for more details.
- 4. For pins that are available as GPIO-only: if the power-on default is Native, the BIOS is still required to configure the pin as
GPIO by writing to the pin's GPIO_USE_SEL register, even though the pin is only available a
- 5. A functional strap also exists on this pin.
- 6. Glitch-less inputs are guaranteed, by circuit design, to de-glitch the input. Glitch-less outputs are guaranteed, by circuit design, to not generate any glitches on the output during power-on.
- 7. The GPIO pins which are capable of generating NMI message when it is configured as input, its GPI_ROUT register is configured NMI functionality and its corresponding GPI NMI Enable (GNE) bit is set. The NMI event is positive edge trigger based on the signal and after GPI Inversion logic.
- 8. When GPIO[5:2] are configured as output GPIOs, they behave in an open drain manner.
9. GPIO 74 or GPIO 57 can be used for NFC on a platform. The NFC option can be set throu
- 9. GPIO 74 or GPIO 57 can be used for NFC on a platform. The NFC option can be set through FITC in Intel ME configuration settings.
- 10. For GPIOs where GPIO vs Native Mode is configured using SPI Soft Strap, the corresponding GPIO_USE_SEL bits for these GPIOs have no effect. The GPIO_USE_SEL bits for these GPIOs may change to reflect the Soft-Strap configuration even though GPIO Lockdown Enable (GLE) bit is set.
- 11. GPIO62 defaults as Native SUSCLK. If this pin is to be configured as GPIO, it is required that the board ensure that the 32.768 kHz toggle rate does not affect the receiving logic of the pin until it is set as GPIO.
- 12. When switching from GPIO at logic 1 to the native functionality, the pin must not glitch low.
- 13. A soft strap (PMC_SOFT_STRAP_2 register[7] GP23MGPIO3_SLPWLAN_SEL) to enable switching between SLP_WLAN_N
. (default) or GP29/MPGIO3. By default the strap is 0b, which enables the SLP_WLAN_N pin function when SUS well When soft strap is loaded and value is 1b, the pin returns to its regular GPIO or MGPIO mode while SLP_WLAN_N function no longer exists. Also take into account of Note 11.
- 14. When strapped as SMI_N, the pin is automatically configured as open drain. The SMI_N function is not the same as the SMI_N events that the GPIOs can be configured to generate, as described in GPI_ROUT and ALT_GPI_SMI_EN.
- 15. The choice of which native mode, SML1ALERT_N or TEMP_ALERT_N, is determined by a soft strap.

2.19 MGPIO Signals

The following signals can be optionally used by the Intel[®] Management Engine (Intel[®] ME) supported applications and appropriately configured by Intel ME Firmware. When configured and used as a manageability function, the associated host GPIO functionality is no longer available. If the manageability function is not used in a platform, the signal can be used as a host General Purpose I/O or a native function.

The manageability signals are referred to as Intel ME GPIO pins (MGPIO pins), which are GPIO pins that can be controlled through Intel ME FW.

2.20 System Management Interface Signals

Table 2-21. SMBus and SMLink Signals

2.21 SPI Signals

Table 2-22. SPI Signals

2.22 Integrated PCH Functional Straps

The SoC integrated PCH implements hardware functional straps that are used to configure specific functions very early in the boot process, before BIOS or software intervention. Some are sampled at the rising edge of PCH_PWROK, while others at the rising edge of RSMRST_N to select configurations (except as noted), and then revert later to their normal usage. When descriptor mode is enabled, the PCH will read Soft Strap data out of the SPI device prior to the de-assertion of reset to both the Intel Management Engine and the host system. In some cases, the soft strap data may override the hardware functional straps.

Table 2-23. SoC Integrated PCH Functional Strap Definitions (Sheet 1 of 3)

Table 2-23. SoC Integrated PCH Functional Strap Definitions (Sheet 2 of 3)

2.23 SoC Integrated Processor Straps

Table 2-24. SoC Integrated Processor Straps Definitions (Sheet 1 of 3)

Table 2-24. SoC Integrated Processor Straps Definitions (Sheet 2 of 3)

Table 2-24. SoC Integrated Processor Straps Definitions (Sheet 3 of 3)

2.24 Reserved/Test Signals

Reserved and NCTF/TP can generally be left unconnected except for the following signals which require special termination. A range is specified where the exact value is not critical.

Table 2-25. Reserved Signals

2.25 Power Groups

Table 2-26. Power Signals (Sheet 1 of 2)

Table 2-26. Power Signals (Sheet 2 of 2)

2.26 Integrated 10 GbE Controller Signals

§

3 Signal Pin States and Termination

This chapter describes the states of each SoC signal during reset sequencing and the S5 (Soft-Off) power state. It also documents what signals have internal pull-up/pulldown/series termination resistors and their values.

3.1 PCH Integrated Pull-Ups and Pull-Downs

Table 3-1. PCH Integrated Pull-Up and Pull-Down Resistors (Sheet 1 of 2)

Table 3-1. PCH Integrated Pull-Up and Pull-Down Resistors (Sheet 2 of 2)

Notes:

- 1. Simulation data shows that these resistor values can range from 10 k Ω to 45 k Ω .
- 2. Simulation data shows that these resistor values can range from 9 k Ω to 50 k Ω .
3. Simulation data shows that these resistor values can range from 15 kO to 40 kQ
- Simulation data shows that these resistor values can range from 15 k Ω to 40 k Ω .
- 4. Simulation data shows that these resistor values can range from 14.25 k Ω to 24.8 k Ω .
- 5. GPIO16 has two native functions The first native function (SATAP4_PCIEP1_SELECT) is selected if the Flex IO soft strap SATAP4_PCIEP1_MODE = 11b and takes precedence over any other assignments to this pin (that is, if this is selected, writes to GPIO_USE_SEL are ignored). If SATAP4_PCIEP1_MODE is not set to 11b, the GPIO_USE_SEL register can be used to select the second native function (SATA4GP) or GPIO functionality. Setting SATAP4_PCIEP1_MODE = 11b also enables an internal pull up resistor in this pin to allow Flexible I/O selection of SATA Port 4 or PCIe Port 1 to be done based on the type of card installed (If sampled value = 1, select SATA; if sampled value = 0, select PCIe). The same behavior is true of pin SATA5GP/GPIO49 when the soft strap SATAP5_PCIEP2_MODE = 11b. Soft straps are handled through FITc.
- 6. When operating as NMI# event indication pin function, the pin is open drain but the PCH provides an internal pull up to ensure the pin does not float.
- 7. This signal is a PCH functional strap; the pull-up or pull-down on this signal is disabled after it is sampled as a PCH functional strap.
- 8. This signal has a weak internal pull-up that always on.
- 9. When operating as SMI# event indication pin function, the pin is open drain but the PCH provides an internal pull up to ensure the pin does not float.
- 10. The pull down is disabled after the pins are driven strongly to logic 0 when PWROK is asserted.
- 11. The pull-up or pull-down on this signal is disabled after RSMRST# de-asserts. Pin must not be driven low until after RSMRST_N de-asserts.
- 12. The internal pull-down on MFG_MODE_STRAP is enabled during reset. However, the pin is strongly driven low after reset.
- 13. The controller link clock and data buffers use internal pull-up or pull-down resistors to drive a logical 1 or 0. 14. Termination resistors may be present if signal is enabled (that is, related Port is not disabled). These resistors appear to be strong pull downs or pull ups on the signals.
- 15. Internal pull down resistor may be enabled in Deep Sx mode based on DSX_CFG configuration bit, as follows: '1' (pin will be driven by platform in Deep Sx) -> Z; - '0' (pin will NOT be driven by platform in Deep Sx) -> Internal pull-down. Refer to DSX_CFG register (RCBA+3334h) for more details.
- 16. N/A
17. This
- This is a 350- Ω normal pull-down, signal will be overridden to logic 1 with pull-up resistor (31 Ω) to VCC 1.05 V.
- 18. N/A
- 19. Regardless of internal pull up or pull down, an external pull up resistor is still required.
20. External pull-up if Intel wired LAN is present (pull up to SUS/DSW based on deepest wa
- External pull-up if Intel wired LAN is present (pull up to SUS/DSW based on deepest wake on LAN support desired).
-
- 21. N/A
22. Wea 22. Weak internal pull-up resistor is enabled when APWROK is de-asserted and is switched to a weak internal pull-down resistor when APWROK and PLTRST# are both asserted.
- 23. Signals are tri-stated with weak pull-up resistors when APWROK is de-asserted. SPI_CS1# remains tristated with a weak pull-up resistor when APWROK and PLTRST# are both asserted.

3.2 Integrated PCH Output Signals Planes and States

[Table 3-2](#page-47-0) shows the power plane associated with the output and I/O signals, as well as the state at various times. Within the table, the following terms are used:

Note: Pin state within table assumes interfaces are idle and default pin configuration for different power states.

Signal levels are the same in S3, S4 and S5, except as noted.

In general, integrated PCH suspend well signal states are indeterminate and undefined and may glitch prior to RSMRST# de-assertion.

PCH core well signal states are indeterminate and undefined and may glitch prior to PCH_PWROK assertion. However, this does not apply to THRMTRIP# as this signal is determinate and defined prior to PCH_PWROK assertion.

DSW indicates PCH Deep Sx Well. This state provides a few wake events and critical context to allow system to draw minimal power in S3, S4 or S5 states. In general, PCH DSW signal states are indeterminate, undefined and may glitch prior to DPWROK assertion. The signals that are determinate and defined prior to DPWROK assertion will have a note added as a reference.

Note: The Intel® Xeon® Processor D-1500 Product Family-based platform does not support DSW state. The DSW power well has been merged with VccSUS3_3.

Table 3-2. PCH Logic Output Signals - Power Plane and States (Sheet 1 of 3)

Table 3-2. PCH Logic Output Signals - Power Plane and States (Sheet 2 of 3)

Notes:

1. This is a strong pull down (or pull up, as applicable).

- 2. The pin output shall not glitch during power up sequence.
- 3. The state of signals in S3-S5 will be defined by Intel ME Policies.
- 4. Based on wake events and ME state. SUSPWRDNACK is always '0' while in M0 or M3, but can be driven to 0 or 1 during the Moff state. SUSPWRDNACK is the default mode of operation. If the system supports DeepSx, then subsequent boots will default to SUSWARN# mode.
- 5. The states of signals on Core and processor power planes are evaluated at the times during PLTRST# and immediately after PLTRST#. The states of the Suspend signals are evaluated at the times during RSMRST# and Immediately after RSMRST#, with an exception to GPIO signals; refer to the EDS for more details on GPIO state after reset.

3.3 Integrated PCH Input and I/O Signals Planes and States

[Table 3-3](#page-50-0) shows the power plane associated with the input and I/O signals, as well as the state at various times. Within the table, the following terms are used:

Note: Pin state within table assumes interfaces are idle and default pin configuration for different power states.

Signal levels are the same in S3, S4, and S5, except as noted.

In general, integrated PCH suspend well signal states are indeterminate and undefined and may glitch prior to RSMRST# de-assertion.

Integrated PCH core well signal states are indeterminate and undefined and may glitch prior to PCH_PWROK assertion. However, this does not apply to THRMTRIP# as this signal is determinate and defined prior to PCH_PWROK assertion.

DSW indicates integrated PCH Deep Sx Well. This state provides a few wake events and critical context to allow system to draw minimal power in S3, S4, or S5 states. In general, PCH DSW signal states are indeterminate, undefined and may glitch prior to DPWROK assertion. The signals that are determinate and defined prior to DPWROK assertion will have a note added as a reference.

Note that Intel® Xeon® Processor D-1500 Product Family-based platform does not support DSW state. The DSW power well has been merged with VccSUS3_3.

Table 3-3. Integrated PCH Input Signals - Power Plane and States (Sheet 1 of 3)

Table 3-3. Integrated PCH Input Signals - Power Plane and States (Sheet 2 of 3)

Table 3-3. Integrated PCH Input Signals - Power Plane and States (Sheet 3 of 3)

Notes: 1. USB3 Rx pins transition from High-Z to IPD after Reset. 2. This is a strong pull down (or pull up, as applicable).

3. Signals could be shared between ports. 4. PCIe Rx pins transition from High-Z to IPD after reset. 5. This is a 350 ohm normal pull-down, the signal will be overridden to logic 1 with pull-up resistor (31 ohms) to 1.05V.

§

Signal DC and Timing Characteristics

4 Signal DC and Timing Characteristics

This section documents the DC characteristics of the following signal groups or interfaces. All data in this chapter are pre-silicon estimates.

4.1 General DC Characteristics

4.1.1 General DC Input Characteristics

DC specifications are defined at the SoC pads, unless otherwise noted. DC specifications are only valid while meeting specifications for case temperature T_{CASE} clock frequency, and input voltages. Care should be taken to read all notes associated with each specification.

4.1.2 SoC Integrated Processor Voltage and Current Specifications

Table 4-1. Voltage Specification (Sheet 1 of 2)

Notes:

Ť

т T

- 1. Unless otherwise noted, all specifications in this table apply to all SKUs. These specifications are based on pre-silicon characterization and will be updated as further data becomes available.
- 2. These voltages are targets only. A SVID controlled variable voltage source should exist on systems in the event that a different voltage is required.
- 3. The VCCIN voltage specification requirements are measured across the remote sense pin pairs (VCCIN_SENSE and VSS_VCCIN_SENSE) on the SoC package. Voltage measurement should be taken with a DC to 100 MHz bandwidth oscilloscope limit (or DC to 20 MHz for older model oscilloscopes), using a 1.5 pF maximum probe capacitance, and 1 MΩ minimum
impedance. The maximum length of the ground wire on the probe should be less than 5 mm to ensure external n system is not coupled in the scope probe.VCCIN is a function of sVID setting and the load. The required voltage droop is depicted in [Figure 4-1](#page-55-0).
- 4. Refer to [Table 4-5, "VCCIN Overshoot Specifications"](#page-57-0) and corresponding figure that the SoC should not be subjected to any static VccIN level that exceeds the VccIN_MAX associated with any particular current. Failure to adhere to this specification can shorten SoC lifetime.
- 5. Minimum VCCIN and maximum ICCIN are specified at the maximum SoC case temperature TCASE. shown in the TMSDG document. ICCIN_MAX is specified at the relative VCC_MAX point on the VCCIN load line. The SoC is capable of drawing ICCIN_MAX for up to 4 ms.
- 6. This specification represents the VccIN reduction or VccIN increase due to each VID transition.
- 7. Baseboard bandwidth is limited to 20 MHz.
- 8. FMB is the flexible motherboard guidelines.
- 9. $DC + AC + Ripple = Total Tolerance$
- 10. VccD tolerance at SoC pins. Tolerance for VR at remote sense is $\pm 3.3\%$ *VccD.
11. The VccD voltage specification requirements are measured across vias on the p
- 11. The VCCD voltage specification requirements are measured across vias on the platform. Choose VCCD vias close to the package and measure with a DC to 100 MHz bandwidth oscilloscope limit (or DC to 20 MHz for older model oscilloscopes), using 1.5 pF maximum probe capacitance, and 1M ohm minimum impedance. The maximum length of the ground wire on the probe should be less than 5 mm to ensure external noise from the system is not coupled in the scope probe.
- 12. VccIN has a Vboot setting of 1.7V and is not included in the PWRGOOD_CPU indication.
- 13. The supply voltage is measured at the package pins. The tolerances shown in [Table 4-1](#page-53-0) are inclusive of all noise from DC up to 20 MHz. In testing, the voltage rails should be measured with a bandwidth limited oscilloscope that has a rolloff of 3 dB/ decade above 20 MHz.

Figure 4-1. V_{CCIN} Static and Transient Tolerance Loadlines

Notes:

- 1. The VCCIN_MIN and VCCIN_MAX loadlines represent static and transient limits. Please see VCCIN Overshoot specifications.
- 2. The loadlines specify voltage limits at the die measured at the VCCIN_SENSE and VSS_VCCIN_SENSE lands. Voltage regulation feedback for voltage regulator circuits must also be taken from SoC VCCIN_SENSE and VSS_VCCIN_SENSE lands.
- 3. The Adaptive Voltage Positioning slope is 1.5 mΩ (mohm) with ±22 mV Tolerance of Band (TOB).
- 4. VCCIN_Vmax = VID(V) 1.5 mΩ * ICCIN +22 mV 5. VCCIN_Vtyp = VID(V) 1.5 mΩ * ICCIN
-
- 6. VCCIN_Vmin = VID(V) 1.5 m Ω * ICCIN 22 mV

Table 4-2. VCCIN Supply Current (IccIN_MAX and ICCIN_TDC) Specification

Unless otherwise noted, all specifications in this table apply to all SKUs. $\frac{1}{2}$.

> 3. For these SKUs, the workload assumed for maintaining P1 frequency at TDP is an average of the SPECint_rate benchmark. Marked frequency may not be maintained on more compute intensive workloads even if there is thermal margin as TDP is enforced by throttling. See [Chapter 1, "Changes to Thermal](#page-7-0) [Design Power \(TDP\) Workload"](#page-7-0) for more information.

Table 4-3. SoC CPU Section Current Specifications

Table 4-4. SoC PCH Section Current Specifications

1. Icc (RTC) data is taken with VccRTC at 3.0V while the system in a mechanical off (G3) state at room

temperature. 2. S0 Iccmax Measurements taken at 110 °C (PCH die junction temperature) and S0 Idle/Sx Iccmax/Sx Idle measurements taken at 50 °C (PCH die junction temperature).

3. The VccSUS3_3 voltage regulator and associated power delivery circuitry should be capable of handling temporary inrush currents up to 2.5 A until the internally generated 1.05V rail (DcpSusByp) ramps. This inrush only occurs when coming from the G3 mechanical off (with missing/dead RTC battery) state.

4.1.3 SoC Integrated Processor Die Voltage Validation

Core voltage (VCCIN) overshoot events at the SoC must meet the specifications in below table when measured across the VccIn_SENSE and VSS_VCCIN_SENSE lands. Overshoot events that are < 10 ns in duration may be ignored. These measurements of SoC die level overshoot should be taken with a 100 MHz bandwidth limited oscilloscope.

The SoC can tolerate short transient overshoot events where VccIN exceeds the VID voltage when transitioning from a high-to-low current load condition. This overshoot can't exceed VID + VOS_MAX (VOS_MAX is the maximum allowable overshoot above VID). These specifications apply to the SoC die voltage as measured across the VccIN_SENSE and VSS_VCCIN_SENSE lands.

Table 4-5. V_{CCIN} Overshoot Specifications

Figure 4-2. V_{CC} Overshoot Example Waveform

Notes:

1. V_{OS_MAX} is the measured overshoot voltage.
2. T_{OS_MAX} is the measured time duration above

2. $T_{\text{OS-MAX}}$ is the measured time duration above VccMAX.
3. VccinMAX = VID + 22 mV

4.1.4 Signal DC Specifications

4.1.4.1 DDR4 Signal

Table 4-6. DDR4 Signal DC Specifications

Notes:

2. The voltage rail VCCD which will be set to 1.2V nominal depending on the voltage of all DIMMs connected to the processor.

Unless otherwise noted, all specifications in this table apply to all processor frequencies.

- 3. VIL is the maximum voltage level at a receiving agent that will be interpreted as a logical low value.
4. VIH is the minimum voltage level at a receiving agent that will be interpreted as a logical high value
- 4. VIH is the minimum voltage level at a receiving agent that will be interpreted as a logical high value.
5. VIH and VOH may experience excursions above VCCD. However, input signal drivers must comply with
- VIH and VOH may experience excursions above VCCD. However, input signal drivers must comply with the signal quality specifications.
- 6. This is the pull down driver resistance. Refer to processor signal integrity models for I/V characteristics. Reset drive does not have a termination.

7. RVTT_TERM is the termination on the DIMM and not controlled by the processor. Please refer to the applicable DIMM datasheet.

- 8. The minimum and maximum values for these signals are programmable by BIOS to one of the pairs.
- 9. Input leakage current is specified for all DDR4 signals.
10. $Vol = Ron * [VCCD/(Ron + Rtt_Eff)]$, where Rtt Eff is
- $Vol = Ron * [VCCD/(Ron + Rtt_Eff)]$, where Rtt_Eff is the effective pull-up resistance of all DIMMs in the system, including ODTs and series resistors on the DIMMs.

4.1.4.2 PECI_CPU DC Specification

This section details the DC specifications for the PECI_CPU pin.

Table 4-7. PECI_CPU DC Specifications

Notes:

1. VCCIOIN supplies the PECI interface. PECI behavior does not affect VCCIOIN min/max specification.
2. It is expected that the PECI driver will take into account, the variance in the receiver input threshold

- 2. It is expected that the PECI driver will take into account, the variance in the receiver input thresholds and consequently, be able to drive its output within safe limits (-0.150V to 0.275*VCCIOIN for the low level and 0.725*VCCIOIN to VCCIOIN+0.150V for the high level).
- 3. The leakage specification applies to powered devices on the PECI bus.
4. One node is counted for each client and one node for the system host.
- 4. One node is counted for each client and one node for the system host. Extended trace lengths might appear as additional nodes.
- 5. Excessive capacitive loading on the PECI line may slow down the signal rise/fall times and consequently limit the maximum bit rate at which the interface can operate.

Figure 4-3. PECI_CPU Input Device Hysteresis

4.1.4.3 Memory and LAN SMBus and LAN I2C DC Specifications

This section details the DC specifications for the DDR_SCL, DDR_SDA, LAN_SMBALRT_N, LAN_SMBCLK, LAN_SMBDATA, LAN_I2C_SCL[1:0] and LAN_I2C_SDA[1:0] pins.

Table 4-8. SMBus DC Specifications

Note: Value obtained through test bench with 50 Ω pull up to VCCIOIN.

4.1.4.4 Integrated Processor JTAG and TAP Signals DC Specifications

This section details the DC specifications for the CPU side JTAG and TAP signals.

Table 4-9. JTAG and TAP Signals DC Specifications

Note:

1. These signals are measured between VIL and VIH.

2. The signal edge rate must be met or the signal must transition monotonically to the asserted state.

4.1.4.5 Serial VID Interface (SVID) DC Specifications

Symbol Parameter Min Typ Max Units Notes VCCIOIN CPU I/O Voltage $VCCI$ OIN - 5% 1.05 $VCCI$ OIN + 5% V 1 V_{IL} Input Low Voltage Signals SVID_DATA, SVIDALERT_N 0.4*VCCIOIN V 1 V_{IH} Input High Voltage Signals SVID_DATA, SVIDALERT_N 0.7*VCCIOIN | | V | 1 V_{OL} Output Low Voltage Signals SVID_CLK, SVID_DATA 0.2*VCCIOIN V 1,5 $\rm V_{Hysteresis}$ |Hysteresis $\rm V_{Hysteresis}$ | $\rm V$ | R_{ON} Buffer On Resistance Signals SVID_CLK, SVID_DATA 4 14 ohm 2 I_{IL} | Input Leakage Current $\begin{array}{|c|c|c|c|c|c|c|c|c|} \hline \end{array}$ 50 $\begin{array}{|c|c|c|c|c|c|c|} \hline \end{array}$ 200 $\begin{array}{|c|c|c|c|c|} \hline \end{array}$ $\begin{array}{|c|c|c|c|c|} \hline \end{array}$ $\begin{array}{|c|c|c|c|c|} \hline \end{array}$ Input Edge Rate Signal: SVIDALERT_N 0.05 | V/ns | 4 Output Edge Rate (50 Ω to VCCIOIN) 0.20 1.5 1.5 4

Table 4-10. Serial VID Interface (SVID) DC Specifications

Notes:

1. V_{CCION} refers to instantaneous V_{CCIOIN} .
2. Measured at 0.31*V_{CCIOIN}
3. Vin between 0V and V_{CCIOIN} (applies to SVIDDATA and SVIDALERT_N only).
4. These are measured between V_{IL and} V_{IH.}
5. Value is obtai

4.1.4.6 SoC Integrated Processor Asynchronous Signal DC Specification

Table 4-11. SoC Misc Signal DC Specifications (Sheet 1 of 2)

Table 4-11. SoC Misc Signal DC Specifications (Sheet 2 of 2)

Notes:

1. Row applies to all signals within group.

2. These are measured between V_{IL and} V_{IH.}
3. CVCCGBE must be stable before driving LAN_XTAL_IN.

4.1.4.7 SoC Integrated PCH General DC Characteristics

Table 4-12. Single-Ended Signal DC Characteristics as Inputs or Outputs (Sheet 1 of 4)

Table 4-12. Single-Ended Signal DC Characteristics as Inputs or Outputs (Sheet 2 of 4)

Table 4-12. Single-Ended Signal DC Characteristics as Inputs or Outputs (Sheet 3 of 4)

Table 4-12. Single-Ended Signal DC Characteristics as Inputs or Outputs (Sheet 4 of 4)

Notes:
1. Th

1. The V_{OH} specification does not apply to open-collector or open-drain drivers. Signals of this type must have an external pull-
up resistor, and that is what determines the high-output voltage level. Refer to Chapter

2. Input characteristics apply when a signal is configured as Input or to signals that are only Inputs. Output characteristics apply when a signal is configured as an Output or to signals that are only Outputs. Refer to [Chapter 2](#page-10-0) for details on signal types.

3. PME_N Input Current Leakage is 1 uA max.
4. CLKIN_33MHZLOOPBACK has a pin capacita 4. CLKIN_33MHZLOOPBACK has a pin capacitance in the range of 1 pF to 12 pF.

5. Only applies to FAST MODE (400 kbits/s).

Table 4-13. Differential Signal DC Characteristics (Sheet 1 of 3)

^{6.} VCCRTC is the voltage applied to the VCCRTC well of the PCH. When the system is in a G3 state, this is generally supplied by the coin cell battery, but for S5 and greater, this is generally VCCSUS3_3.

Table 4-13. Differential Signal DC Characteristics (Sheet 2 of 3)

Table 4-13. Differential Signal DC Characteristics (Sheet 3 of 3)

Notes:

1. PCI Express* mVdiff p-p = 2*|PETp[x] – PETn[x]|; PCI Express mVdiff p-p = 2*|PERp[x] – PERn[x]|

2. SATA Vdiff, RX (V_{IMAX}/V_{IMIN}) is measured at the SATA connector on the receiver side (generally, the motherboard connector), where SATA mVdiff $p-p = 2^*$ SATA[x]RXP – SATA[x]RXN].

- 3. SATA Vdiff, tx (V_{OMIN}/V_{OMAX}) is measured at the SATA connector on the transmit side (generally, the motherboard connector),
where SATA mVdiff p-p = 2*|SATA[x]TXP SATA[x]TXN|
- 4. V_{DI} = | USBPx[P] USBPx[N] |
5. Includes VDI range.
-
- 6. Applies to Low-Speed/Full-Speed USB.
- 7. Applies to High-Speed USB 2.0.
8. USB 3.0 mVdiff $p-p = 2*115B3B$ USB 3.0 mVdiff p-p = 2^* |USB3Rp[x] – USB3Rn[x]|; USB 3.0 mVdiff p-p = 2^* |USB3Tp[x] – USB3Tn[x]|
- 9. Max PCIe* DC voltage is 3.6V, as specified in *PCIe Specification*, and maximum spike should not exceed 5.4V as specified in
- JEDEC specification JESD78.

4.1.4.8 KR Interface AC/DC Specifications

The KR interface supports the 10GBASE-KR electrical specification defined in IEEE802.3ap clause 72.

4.1.4.9 KX Interface AC/DC Specifications

The KX interface supports the 1000BASE-KX electrical specification defined in IEEE802.3ap clause 70.

4.1.4.10 Network Controller Sideband Interface (NC-SI) AC/DC Specifications

The NC-SI interface supports the NC-SI electrical specification as defined by the Distributed Management Task Force.

4.1.4.11 LAN_SPI, LAN_MDIO and LAN_SPD DC Specifications

This section details the DC specifications for the LAN[1:0]_MDIO[1:0], LAN[1:0]_MDIO_DIR_CTL, LAN[1:0]_SDP[1:0]_[1:0], LAN[1:0]_FLASH_CLK, $LAN[1:0]$ FLSH CS N, LAN $[1:0]$ FLSH DI and LAN $[1:0]$ FLSH DO pins.

Table 4-14. LAN SPI, MDIO and SDP DC Specifications

It is permissible to violate this specification if the SoC starts driving the strap before the hold time ends. The SoC will not drive an output which is also a strap until after it has latched the strap value.

§

5 Operating Conditions and Power Requirements

Note: The information provided in this chapter is preliminary and subject to change. It is based on both pre-silicon engineering estimates and some post-silicon measurements. As they arise, notable changes to the operational characteristics and parameters will be updated in future revisions of this document.

5.1 Absolute Maximum and Minimum Ratings

Below table specifies absolute maximum and minimum ratings. At conditions outside functional operation condition limits, but within absolute maximum and minimum ratings, neither functionality nor long-term reliability can be expected. If a device is returned to conditions within functional operation limits after having been subjected to conditions outside these limits, but within the absolute maximum and minimum ratings, the device may be functional, but with its lifetime degraded depending on exposure to conditions exceeding the functional operation condition limits.

Although the processor contains protective circuitry to resist damage from Electro-Static Discharge (ESD), precautions should always be taken to avoid high static voltages or electric fields.

Table 5-1. SoC Integrated Processor Absolute Minimum and Maximum Ratings

Notes:

1. For functional operation, all processor electrical, signal quality, mechanical, and thermal specifications must be satisfied.

2. Overshoot and undershoot voltage guidelines for input, output, and I/O signals are outlined in [Overshoot/](#page-70-0) [Undershoot Tolerance.](#page-70-0) Excessive overshoot or undershoot on any signal will likely result in permanent damage to the processor.

Table 5-2. SoC Integrated PCH Absolute Maximum Ratings

The table above specifies absolute maximum and minimum ratings. At conditions outside functional operation condition limits, but within absolute maximum and minimum ratings, neither functionality nor long-term reliability can be expected. If a device is returned to conditions within functional operation limits after having been subjected to conditions outside these limits (but within the absolute maximum and minimum ratings) the device may be functional, but with its lifetime degraded depending on exposure to conditions exceeding the functional operation condition limits.

At conditions exceeding absolute maximum and minimum ratings, instantaneous device damage can occur. If a device is subjected to these conditions for any length of time, it will either not function or its reliability will be severely degraded when returned to conditions within the functional operating condition limits.

Although the SoC contains protective circuitry to resist damage from Electrostatic Discharge (ESD), precautions should always be taken to avoid high static voltages or electric fields.

5.2 Storage Conditions Specifications

Environmental storage condition limits define the temperature and relative humidity limits to which the device is exposed to while being stored in a moisture barrier bag. The specified storage conditions are for component level prior to board attach (see notes in the table for post board attach limits).

The table below specifies absolute maximum and minimum storage temperature limits which represent the maximum or minimum device condition beyond which damage, latent or otherwise, may occur. The table also specifies sustained storage temperature, relative humidity, and time-duration limits. These limits specify the maximum or minimum device storage conditions for a sustained period of time. At conditions outside sustained limits, but within absolute maximum and minimum ratings, quality and reliability may be affected.

Table 5-3. Storage Condition Ratings

Notes:

1. TABSOLUTE STORAGE applies to the un-assembled component only and does not apply to the shipping media, moisture barrier bags or desiccant. Refers to a component device that is not assembled in a board or socket that is not to be electrically connected to a voltage reference or I/O signals.

- 2. Specified temperatures are based on data collected. Exceptions for surface mount re-flow are specified by applicable JEDEC J-STD-020 and MAS documents. The JEDEC, J-STD-020 moisture level rating and associated handling practices apply to all moisture sensitive devices removed from the moisture barrier bag.
- 3. Post board attach storage temperature limits are not specified for non-Intel branded boards. Consult your board manufacturer for storage specifications

5.2.1 Overshoot/Undershoot Tolerance

Overshoot (or undershoot) is the absolute value of the maximum voltage above or below V_{SS} , see below figure. The overshoot/undershoot specifications limit transitions beyond \overline{V}_{CCD} or V_{SS} due to the fast signal edge rates. The processor can be damaged by single and/or repeated overshoot or undershoot events on any input, output, or I/O buffer if the charge is large enough (that is, if the over/undershoot is great enough). Determining the impact of an overshoot/undershoot condition requires knowledge of the magnitude, the pulse direction, and the Activity Factor (AF). Permanent damage to the processor is the likely result of excessive overshoot/undershoot.

Baseboard designs which meet signal integrity and timing requirements and which do not exceed the maximum overshoot or undershoot limits listed in below table will insure reliable IO performance for the lifetime of the processor.

Table 5-4. Processor I/O Overshoot/Undershoot Specifications

Notes:

2. Refer to [Figure 5-1](#page-71-0) for description of allowable overshoot/undershoot magnitude and duration.
3. Tch is the minimum high pulse width duration. It is nominally 1/2 of the DDR clock period.

Tch is the minimum high pulse width duration. It is nominally $\frac{1}{2}$ of the DDR clock period.

^{1.} These specifications are measured at the processor pad.

Figure 5-1. Maximum Acceptable Overshoot/Undershoot Waveform

5.2.1.1 Overshoot/Undershoot Magnitude

Overshoot/Undershoot magnitude describes the maximum potential difference between a signal and its voltage reference level. For the processor, both overshoot and undershoot magnitude are referenced to V_{SS} . It is important to note that the overshoot and undershoot conditions are separate and their impact must be determined independently.

The pulse magnitude and duration, and activity factor must be used to determine if the overshoot/undershoot pulse is within specifications.

5.2.1.2 Overshoot/Undershoot Pulse Duration

Overshoot/undershoot pulse duration describes the total amount of time that an overshoot/undershoot event exceeds the overshoot/undershoot reference voltage. The total time could encompass several oscillations above the reference voltage. Multiple overshoot/undershoot pulses within a single overshoot/undershoot event may need to be measured to determine the total pulse duration.

Note: Oscillations below the reference voltage cannot be subtracted from the total overshoot/ undershoot pulse duration.

5.2.1.3 Activity Factor

Activity Factor (AF) describes the frequency of overshoot (or undershoot) occurrence relative to a clock. Since the highest frequency of assertion of any common clock signal is every other clock, an $AF = 0.1$ indicates that the specific overshoot (or undershoot) waveform occurs every other clock cycle.

The specification provided in the table shows the maximum pulse duration allowed for a given overshoot/undershoot magnitude at a specific activity factor. Each table entry is independent of all others, meaning that the pulse duration reflects the existence of overshoot/undershoot events of that magnitude ONLY. A platform with an overshoot/ undershoot that just meets the pulse duration for a specific magnitude where the AF < 0.1, means that there can be no other overshoot/undershoot events, even of lesser magnitude (note that if $AF = 0.1$, then the event occurs at all times and no other events can occur).

5.2.1.4 Reading Overshoot/Undershoot Specification Tables

The overshoot/undershoot specification for the processor is not a simple single value. Instead, many factors are needed to determine the over/undershoot specification. In addition to the magnitude of the overshoot, the following parameters must also be known: the width of the overshoot and the Activity Factor (AF). To determine the allowed overshoot for a particular overshoot event, the following must be done:

- 1. Determine the signal group a particular signal falls into.
- 2. Determine the magnitude of the overshoot or the undershoot (relative to VSS).
- 3. Determine the activity factor (How often does this overshoot occur?).
- 4. Next, from the appropriate specification table, determine the maximum pulse duration (in nanoseconds) allowed.
- 5. Compare the specified maximum pulse duration to the signal being measured. If the pulse duration measured is less than the pulse duration shown in the table, then the signal meets the specifications.

Undershoot events must be analyzed separately from overshoot events as they are mutually exclusive.

5.2.1.5 Determining if a System Meets the Overshoot/Undershoot Specifications

The overshoot/undershoot specifications listed in [Table 4-5](#page-57-0) specify the allowable overshoot/undershoot for a single overshoot/undershoot event. However most systems will have multiple overshoot and/or undershoot events that each have their own set of parameters (duration, AF and magnitude). While each overshoot on its own may meet the overshoot specification, when you add the total impact of all overshoot events, the system may fail. A guideline to ensure a system passes the overshoot and undershoot specifications is shown below.

- 1. If only one overshoot/undershoot event magnitude occurs, ensure it meets the over/undershoot specifications, OR
- 2. If multiple overshoots and/or multiple undershoots occur, measure the worst case pulse duration for each magnitude and compare the results against the $AF = 0.1$ specifications. If all of these worst case overshoot or undershoot events meet the specifications (measured time \leq specifications) in the table (where AF= 0.1), then the system passes.

6 Intel® QuickData Technology Configuration Registers

The Intel® Xeon® Processor D-1500 NS product family implements the Intel® QuickData Technology 3.2 DMA engine. This is different from the Intel QuickData Technology 3.3 DMA present in the Intel Xeon Processor D-1500 product family.

The DMA is mapped to CPUBUSNO(0), Device 4, Functions 0-7. CPUBUSNO(0) is programmable by BIOS.

This section describes the standard PCI configuration registers and device specific Configuration Registers related to below:

- Intel QuickData Technology 3.2 DMA Registers Device 4, Function 0 -7
- Intel QuickData Technology 3.2 MMIO Registers

6.1 Device 4 Function 0-7

Intel QuickData Technology PCI Configuration Registers.

6.1.1 vid

6.1.2 did

6.1.3 pcicmd

6.1.4 pcists

6.1.5 rid

6.1.6 ccr

6.1.7 clsr

6.1.8 hdr

6.1.9 cb_bar

Intel QuickData Technology Base Address Register

6.1.10 svid

6.1.11 sdid

6.1.12 capptr

6.1.13 intl

6.1.14 intpin

6.1.15 devcfg

This DEVCFG is for Function 0 only.

6.1.16 msixcapid

MSI-X Capability ID

6.1.17 msixnxtptr

MSI-X Next Pointer

6.1.18 msixmsgctl

MSI-X Message Control

6.1.19 tableoff_bir

MSI-X Table Offset and BAR Indicator

6.1.20 pbaoff_bir

6.1.21 capid

The PCI Express Capability List register enumerates the PCI Express Capability structure in the PCI 3.0 configuration space.

6.1.22 nextptr

The PCI Express Capability List register enumerates the PCI Express Capability structure in the PCI 3.0 configuration space.

6.1.23 expcap

The PCI Express Capabilities register identifies the PCI Express device type and associated capabilities.

6.1.24 devcap

The PCI Express Device Capabilities register identifies device specific information for the device.

6.1.25 devcon

The PCI Express Device Control register controls PCI Express specific capabilities parameters associated with the device.

6.1.26 devsts

The PCI Express Device Status register provides information about PCI Express device specific parameters associated with the device.

6.1.27 devcap2

6.1.28 devcon2

6.1.29 pmcap

Power Management Capability

The Power Management Capabilities Register defines the capability ID, next pointer and other power management related support. The following power management registers/ capabilities are added for software compliance.

6.1.30 pmcsr

Power Management Control and Status

This register provides status and control information for Power Management events in the PCI Express port of the IIO.

6.1.31 dmauncerrsts

DMA Cluster Uncorrectable Error Status

6.1.32 dmauncerrmsk

DMA Cluster Uncorrectable Error Mask

6.1.33 dmauncerrsev

DMA Cluster Uncorrectable Error Severity

This register controls severity of uncorrectable DMA unit errors between fatal and nonfatal.

6.1.34 dmauncerrptr

DMA Cluster Uncorrectable Error Pointer

6.1.35 dmaglberrptr

DMA Cluster Global Error Pointer

6.1.36 chanerr_int

Internal DMA Channel Error Status Registers

6.1.37 chanerrmsk_int

Internal DMA Channel Error Mask Registers

6.1.38 chanerrsev_int

Internal DMA Channel Error Severity Registers

6.1.39 chanerrptr

DMA Channel Error Pointer

6.2 Device 4 Function 0 - 7 MMIO Region Intel QuickData Technology BARs

Intel QuickData Technology MMIO Register used to control the DMA functionality. The Intel QuickData Technology BAR register points to the based address to these registers.

All of these registers are accessible from only the processor. The IIO supports accessing the Intel QuickData Technology device memory-mapped registers via QWORD reads and writes. The offsets indicated in the following table are from the Intel QuickData Technology BAR value.

6.2.1 chancnt

Channel Count

The Channel Count register specifies the number of channels that are implemented.

6.2.2 xfercap

Transfer Capacity

The Transfer Capacity specifies the minimum of the maximum DMA transfer size supported on all channels.

6.2.3 genctrl

DMA General Control

The DMA Control register provides for general control operations.

6.2.4 intrctrl

The Interrupt Control register provides for control of DMA interrupts.

6.2.5 attnstatus

Attention Status

6.2.6 cbver

The Intel QuickData Technology version register field indicates the version of the Intel QuickData Technology specification that the IIO implements. The most significant 4-bits (range 7:4) are the major version number and the least significant 4-bits (range 3:0) are the minor version number. The IIO implementation for this Intel QuickData Technology version is 3.2 encoded as 0b0011 0010.

6.2.7 intrdelay

Interrupt Delay

6.2.8 cs_status

Chipset Status

6.2.9 dmacapability

6.2.10 dcaoffset

6.2.11 cbprio

Intel QuickData Technology DMA Priority Register

6.2.12 chanctrl

The Channel Control register controls the behavior of the DMA channel when specific events occur such as completion or errors.

6.2.13 dma_comp

DMA Compatibility Register

6.2.14 chancmd

DMA Channel Command Register

Setting more than one of these bits with the same write operation will result in an fatal error affiliated.

6.2.15 dmacount

DMA Descriptor Count Register

6.2.16 chansts_0

Channel Status 0 Register

The Channel Status Register records the address of the last descriptor completed by the DMA channel.

6.2.17 chansts_1

Channel Status 1 Register

The Channel Status Register records the address of the last descriptor completed by the DMA channel.

6.2.18 chainaddr_0

Descriptor Chain Address 0 Register

This register is written by the processor to specify the first descriptor to be fetched by the DMA channel.

6.2.19 chainaddr_1

Descriptor Chain Address 1 Register

This register is written by the processor to specify the first descriptor to be fetched by the DMA channel.

6.2.20 chancmp_0

Channel Completion Address 0 Register

This register specifies the address where the DMA channel writes the completion status upon completion or an error condition i.e., it writes the contents of the CHANSTS register to the destination as pointed by the CHANCMP register.

6.2.21 chancmp_1

Channel Completion Address 1 Register

This register specifies the address where the DMA channel writes the completion status upon completion or an error condition i.e., it writes the contents of the CHANSTS register to the destination as pointed by the CHANCMP register.

6.2.22 chanerr

The Channel Error Register records the error conditions occurring within a given DMA channel.

6.2.23 chanerrmsk

Channel Error Mask Register

6.2.24 dcactrl

DCA Control

6.2.25 dca_ver

DCA Version Number Register

6.2.26 dca_reqid_offset

DCA Requester ID Offset

6.2.27 csi_capability

Intel QPI Compatibility Register

6.2.28 pcie_capability

PCI Express Capability Register

6.2.29 csi_cap_enable

Intel QPI Capability Enable Register

6.2.30 pcie_cap_enable

PCI Express Capability Enable Register

6.2.31 apicid_tag_map

APICID to Tag Map Register

When DCA is disabled, DMA engine uses all 1s in the tag field of the write.

This register is setup by the BIOS for the Intel QuickData Technology driver to read. The BIOS will map APICID[7:5] to bits Tag[2:0]. The BIOS should set Tag[4] to prevent implicit TPH cache target unless it is intended.

6.2.32 dca_reqid[0:1]

Global DCA Requester ID Table Registers

6.2.33 msgaddr

MSI-X Lower Address Registers

6.2.34 msgupaddr

MSI-X Upper Address Registers

6.2.35 msgdata

MSI-X Data Registers

6.2.36 vecctrl

MSI-X Vector Control Registers

